

1. Global joint venture starts operations as WeEn Semiconductors

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Product data sheet

1. General description

Planar passivated SCR with sensitive gate in a SIP3 (SOT82) plastic package intended for use in general purpose switching and phase control applications. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

2. Features and benefits

- Sensitive gate
- Planar passivated for voltage ruggedness and reliability
- Direct triggering from low power drivers and logic ICs

3. Applications

- Adapters
- Battery powered applications
- Industrial automation

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|---------------------|--|--|-----|-----|-----|-----|------|
| V_{DRM} | repetitive peak off- state voltage | | [1] | - | - | 400 | V |
| V_{RRM} | repetitive peak reverse voltage | | | - | - | 400 | V |
| I _{TSM} | non-repetitive peak on- state current | half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5 | | - | - | 35 | A |
| I _{T(RMS)} | RMS on-state current | half sine wave; $T_{mb} \le 113 ^{\circ}\text{C}$; Fig. 2; Fig. 3 | | - | - | 4 | Α |
| Static charact | teristics | | | | | | |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 7$ | | - | 15 | 200 | μA |

^[1] Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/µs.





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5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-----------------------------------|--------------------|---|
| 1 | K | cathode | [[]] | A |
| 2 | Α | anode | | G sym037 |
| 3 | G | gate | \\\ | · |
| mb | A | mounting base; connected to anode | | |
| | | | SIP3 (SOT82) | |

6. Ordering information

Table 3. Ordering information

| Type number | Package | | |
|-------------|---------|---|---------|
| | Name | Description | Version |
| BT148-400R | SIP3 | plastic single-ended package; 3 leads (in-line) | SOT82 |

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7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | | Min | Max | Unit |
|---------------------|--------------------------------------|---|------------|-----|-----|------------------|
| V_{DRM} | repetitive peak off-state voltage | | [1] | - | 400 | V |
| V_{RRM} | repetitive peak reverse voltage | | | - | 400 | V |
| I _{T(AV)} | average on-state current | half sine wave; T _{mb} ≤ 113 °C; <u>Fig. 1</u> | | - | 2.5 | Α |
| I _{T(RMS)} | RMS on-state current | half sine wave; $T_{mb} \le 113 \text{ °C}$; Fig. 2; Fig. 3 | | - | 4 | Α |
| I _{TSM} | non-repetitive peak on-state current | half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 10 \text{ ms}$; Fig. 4; Fig. 5 | | - | 35 | А |
| | | half sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 8.3 \text{ms}$ | | - | 38 | Α |
| I ² t | I ² t for fusing | t _p = 10 ms; SIN | | - | 6.1 | A ² s |
| dI _T /dt | rate of rise of on-state current | $I_T = 10 \text{ A}$; $I_G = 50 \text{ mA}$; $dI_G/dt = 50 \text{ mA}/$ µs | | - | 50 | A/µs |
| I _{GM} | peak gate current | | | - | 2 | Α |
| V_{RGM} | peak reverse gate voltage | | | - | 5 | V |
| P_{GM} | peak gate power | | | - | 5 | W |
| P _{G(AV)} | average gate power | over any 20 ms period | | - | 0.5 | W |
| T _{stg} | storage temperature | | | -40 | 150 | °C |
| Tj | junction temperature | | <u>[2]</u> | - | 125 | °C |

^[1] Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/µs.

^[2] Operation above 110°C may require the use of a gate to cathode resistor of $1k\Omega$ or less.

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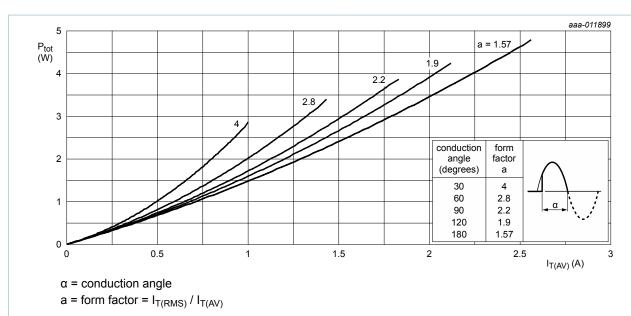


Fig. 1. Total power dissipation as a function of average on-state current; maximum values

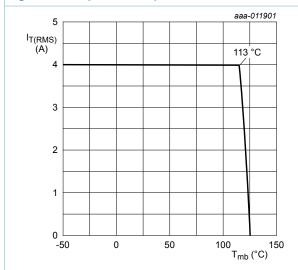
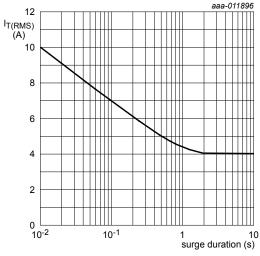


Fig. 2. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50 \text{ Hz}; T_{mb} = 113 \,^{\circ}\text{C}$

Fig. 3. RMS on-state current as a function of surge duration; maximum values

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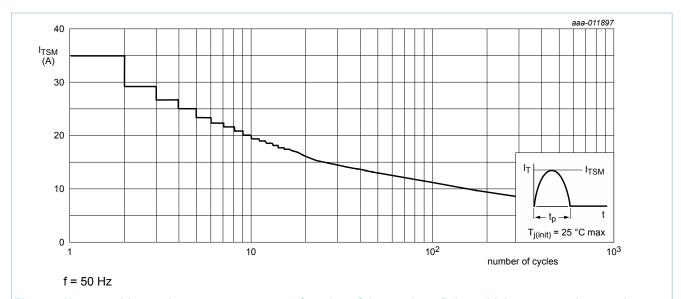


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

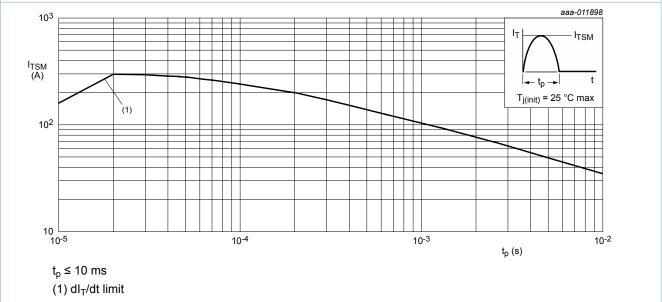


Fig. 5. Non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; maximum values

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8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---|-------------|-----|-----|-----|------|
| R _{th(j-mb)} | thermal resistance from junction to mounting base | Fig. 6 | - | - | 2.5 | K/W |
| R _{th(j-a)} | thermal resistance from junction to ambient | in free air | - | 95 | - | K/W |

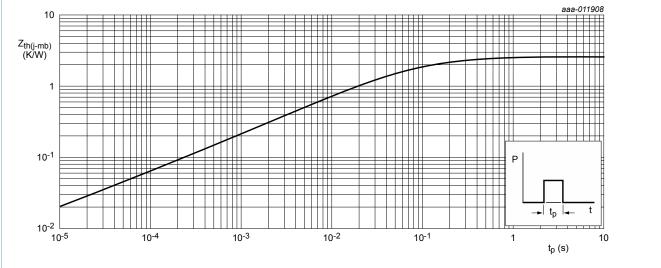


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse width

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9. Characteristics

Table 6. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|-----------------------------------|--|-----|------|-----|------|
| Static char | acteristics | | , | | | |
| I _{GT} | gate trigger current | V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u> | - | 15 | 200 | μA |
| I _L | latching current | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 8$ | - | 0.17 | 10 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | 0.1 | 6 | mA |
| V_{T} | on-state voltage | I _T = 5 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.23 | 1.8 | V |
| V _{GT} | gate trigger voltage | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11 | - | 0.4 | 1 | V |
| | | $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 110 \text{ °C};$ Fig. 11 | 0.1 | 0.2 | - | V |
| I _D | off-state current | V _D = 400 V; T _j = 125 °C | - | 0.1 | 0.5 | mA |
| I _R | reverse current | V _R = 400 V; T _j = 125 °C | - | 0.1 | 0.5 | mA |
| Dynamic cl | haracteristics | | | ' | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 268 V; T_j = 125 °C; R_{GK} = 100 Ω; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; Fig. 12 | - | 50 | - | V/µs |
| t _{gt} | gate-controlled turn-on time | I_{TM} = 10 A; V_D = 400 V; I_G = 5 mA; $dI_G/$ dt = 0.2 A/µs; T_j = 25 °C | - | 2 | - | μs |
| t _q | commutated turn-off time | $\begin{split} &V_{DM} = 268 \text{ V; } T_j = 125 \text{ °C; } I_{TM} = 8 \text{ A;} \\ &V_R = 10 \text{ V; } (dI_T/dt)_M = 10 \text{ A/µs; } dV_D/\\ &dt = 2 \text{ V/µs; } R_{GK} = 1 \text{ k}\Omega; \text{ (V}_{DM} = 67\% \text{ of } \\ &V_{DRM}) \end{split}$ | - | 100 | - | μs |

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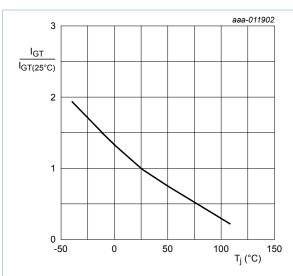


Fig. 7. Normalized gate trigger current as a function of junction temperature

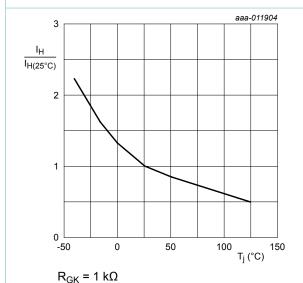
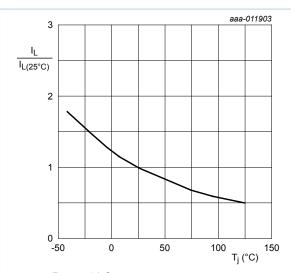
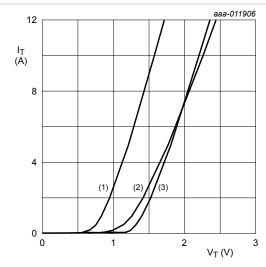


Fig. 9. Normalized holding current as a function of junction temperature



 $R_{GK} = 1 k\Omega$

Fig. 8. Normalized latching current as a function of junction temperature



 $V_0 = 1.26 \text{ V}; R_s = 0.099 \Omega$

(1) T_i = 125 °C; typical values

(2) T_i = 125 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

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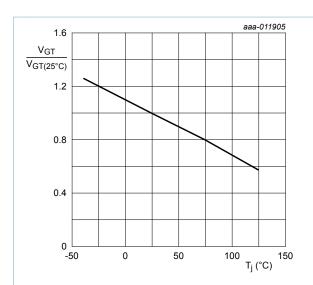


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

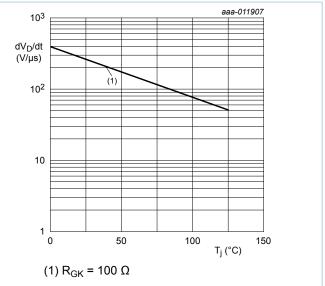


Fig. 12. Critical rate of rise of off-state voltage as a function of junction temperature; typical values

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10. Package outline

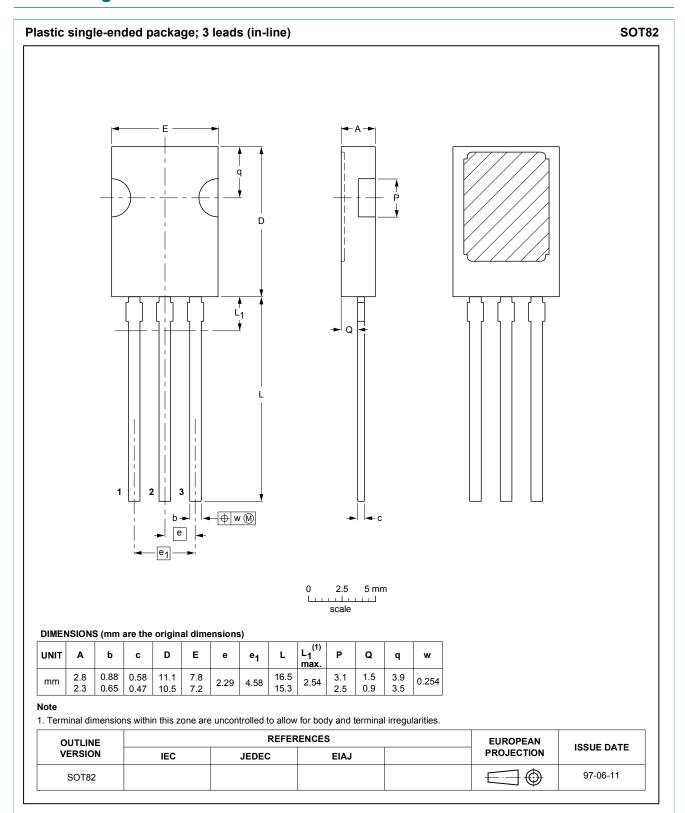


Fig. 13. Package outline SIP3 (SOT82)

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12. Contents

| 1 | General description | 1 |
|------|-------------------------|----|
| 2 | Features and benefits | 1 |
| 3 | Applications | 1 |
| 4 | Quick reference data | 1 |
| 5 | Pinning information | 2 |
| 6 | Ordering information | 2 |
| 7 | Limiting values | 3 |
| 8 | Thermal characteristics | 6 |
| 9 | Characteristics | 7 |
| 10 | Package outline | 10 |
| 11 | Legal information | 11 |
| 11.1 | Data sheet status | 11 |
| 11.2 | Definitions | 11 |
| 11.3 | Disclaimers | 11 |
| 11.4 | Trademarks | 12 |

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